

MOSFET - SiC Power, Single N-Channel

1200 V, 35 mΩ, 87 A



KXMT120R40T8

Features

- Typ. $R_{DS(on)} = 35\text{ m}\Omega$
- Ultra Low Gate Charge ($Q_{G(tot)} = 97\text{ nC}$)
- Capacitance ($C_{oss} = 148\text{ pF}$)
- 100% UIL Tested

Typical Applications

- UPS
- DC/DC Converter
- Boost Inverter

MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	1200	V
Gate-to-Source Voltage	V_{GS}	-7/23	V
Recommended turn on Gate-to-Source Voltage	$T_C < 175^\circ\text{C}$	$V_{GS, on}$	15-18 V
Recommended turn off Gate-to-Source Voltage		$V_{GS, off}$	0 V
Continuous Drain Current $R_{\theta JC}$	Steady State	$T_C = 25^\circ\text{C}$	87 A
		$T_C = 100^\circ\text{C}$	62 A
Power Dissipation $R_{\theta JC}$	Steady State	$T_C = 25^\circ\text{C}$	365 W
		$T_C = 150^\circ\text{C}$	60 W
Pulsed Drain Current (Note 2)	$T_A = 25^\circ\text{C}$ V_{ES}	I_{DM}	304 A
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to +175	$^\circ\text{C}$
Source Current (BodyDiode)	I_S	87	A

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

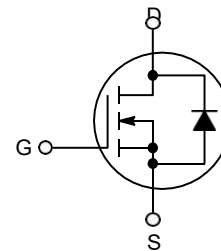
THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Max	Unit
Junction-to-Case (Note 1)	$R_{\theta JC}$	0.41	0.63	$^\circ\text{C/W}$
Junction-to-Ambient (Note 1)	$R_{\theta JA}$	32.48	-	$^\circ\text{C/W}$

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Repetitive rating, limited by max junction temperature.

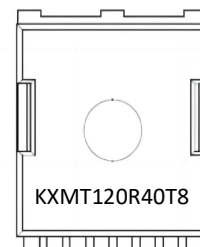
$V_{(BR)DSS}$	$R_{DS(on)}$ MAX	I_D MAX
1200 V	35 mΩ	87 A

N-CHANNEL MOSFET



TOLL-8L

MARKING DIAGRAM



Publication Order Number:
KXMT120R40T8

KXMT120R40T8

Static Electrical Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 100\text{ }\mu\text{A}$		1200	1360	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS} = 0\text{ V}, V_{DS} = 1200\text{ V}, T_J = 25\text{ }^\circ\text{C}$		0.97	100	μA
		$V_{GS} = 0\text{ V}, V_{DS} = 1200\text{ V}, T_J = 175\text{ }^\circ\text{C}$		3	100	
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = -10\text{ V}, V_{DS} = 0\text{ V}$		-0.1	-100	nA
		$V_{GS} = 25\text{ V}, V_{DS} = 0\text{ V}$		1	100	
Transconductance	g_{fs}	$V_{DS} = 20\text{ V}, I_D = 20\text{ A}, T_J = 25\text{ }^\circ\text{C}$		10.55		S
		$V_{DS} = 20\text{ V}, I_D = 20\text{ A}, T_J = 175\text{ }^\circ\text{C}$		11.28		
Drain-Source On Resistance	$R_{DS(on)}$	$V_{GS} = 20\text{ V}, I_D = 20\text{ A}, T_J = 25\text{ }^\circ\text{C}$		35		m Ω
		$V_{GS} = 20\text{ V}, I_D = 20\text{ A}, T_J = 175\text{ }^\circ\text{C}$		48		
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 10\text{ mA}, T_J = 25\text{ }^\circ\text{C}$		2.7		V
		$V_{GS} = V_{DS}, I_D = 10\text{ mA}, T_J = 175\text{ }^\circ\text{C}$		2		

Dynamic Electrical Characteristics

Parameter	Symbol	Test Conditions	Typ	Unit
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{ V}, V_{DS} = 1000\text{ V},$ $f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$	1972	μF
Output Capacitance	C_{OSS}		148	
Reverse Transfer Capacitance	C_{RSS}		3	
C_{OSS} Stored Energy	E_{OSS}		155	
Turn-On Switching Loss	E_{ON}	$V_{GS} = -4/20\text{ V}, V_{DS} = 800\text{ V},$ $I_D = 20\text{ A}, R_G = 2\text{ }\Omega, \text{ Inductive Load}$ $T_J = 25\text{ }^\circ\text{C}$ $T_J = 175\text{ }^\circ\text{C}$	385	μJ
			361	
Turn-Off Switching Loss	E_{OFF}	$V_{GS} = -4/20\text{ V}, V_{DS} = 800\text{ V},$ $I_D = 20\text{ A}, R_G = 2\text{ }\Omega, \text{ Inductive Load}$ $T_J = 25\text{ }^\circ\text{C}$ $T_J = 175\text{ }^\circ\text{C}$	484	
			562	
Total Gate Charge	$Q_{G(tot)}$	$V_{GS} = -4/20\text{ V}, V_{DS} = 800\text{ V}, I_D = 20\text{ A}$	97	nC
Gate-Source Charge	Q_{GS}		29	
Gate-Drain Charge	Q_{GD}		26	
Internal Gate Resistance	R_G	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$	0.61	Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = -4/20\text{ V}, V_{DS} = 800\text{ V},$ $I_D = 20\text{ A}, R_G = 2\text{ }\Omega, T_J = 175\text{ }^\circ\text{C}$ Inductive Load	12	ns
Rise Time	t_r		6	
Turn-Off Delay Time	$t_{d(off)}$		28	
Fall Time	t_f		24	

KXMT120R40T8

Reverse Diode Characteristic

Parameter	Symbol	Test Conditions	Typ	Unit
Continuous Drain-to-Source Diode Forward Current	I_{SD}	$V_{GS} = 0\text{ V}, T_J = 25\text{ }^\circ\text{C}$	87	A
Forward Diode Voltage	V_{SD}	$V_{GS} = 0\text{ V}, I_{SD} = 20\text{ A}, T_J = -55\text{ }^\circ\text{C}$	4.4	V
		$V_{GS} = 0\text{ V}, I_{SD} = 20\text{ A}, T_J = 25\text{ }^\circ\text{C}$	3.3	
		$V_{GS} = 0\text{ V}, I_{SD} = 20\text{ A}, T_J = 175\text{ }^\circ\text{C}$	3.2	
Pulsed Drain-to-Source Diode Forward Current (Note 2)	I_{SDM}	$T_J = 25\text{ }^\circ\text{C}$	304	A
Reverse Recovery Time	t_{RR}	$V_{GS} = -4\text{ V}, I_{SD} = 20\text{ A}, V_{DS} = 800\text{ V},$ $di_S/dt = 1000\text{ A}/\mu\text{s}, T_J = 25\text{ }^\circ\text{C}$ Q_{fir} includes also Q_C	19.9	ns
Reverse Recovery Charge	Q_{RR}		140	nC
Peak Reverse Recovery Current	I_{RRM}		12.8	A
Reverse Recovery Energy	E_{RR}		0.07	mJ

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

KXMT120R40T8

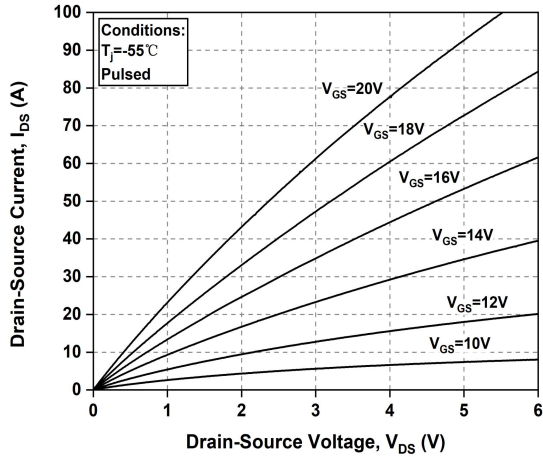


Figure 1. Output characteristics, $T_j = -55^\circ\text{C}$

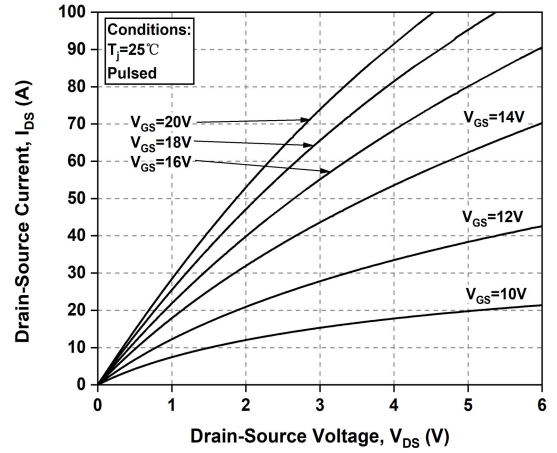


Figure 2. Output characteristics, $T_j = 25^\circ\text{C}$

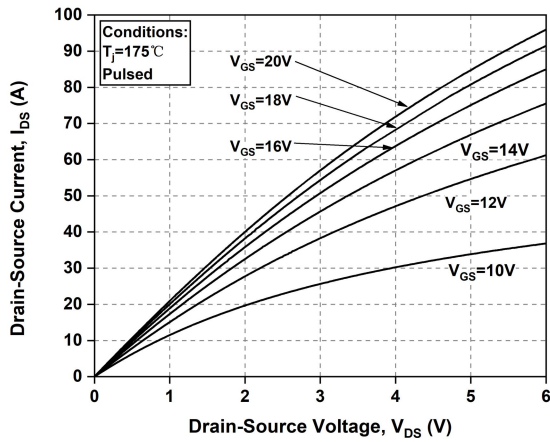


Figure 3. Output characteristics, $T_j = 175^\circ\text{C}$

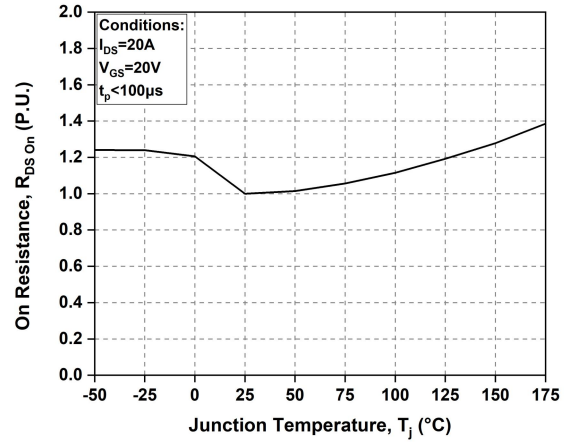


Figure 4. Normalized on-resistance vs. temperature

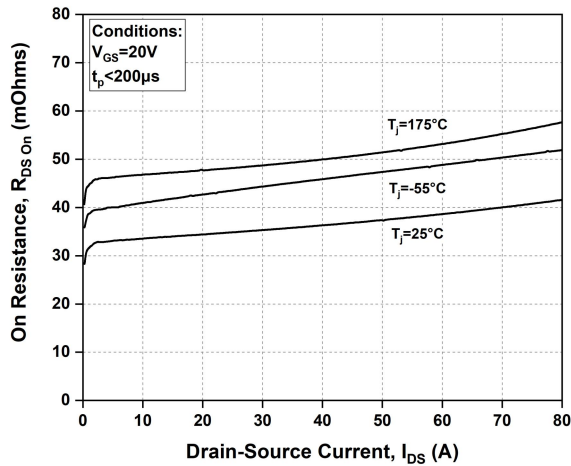


Figure 5. On-resistance vs. drain current

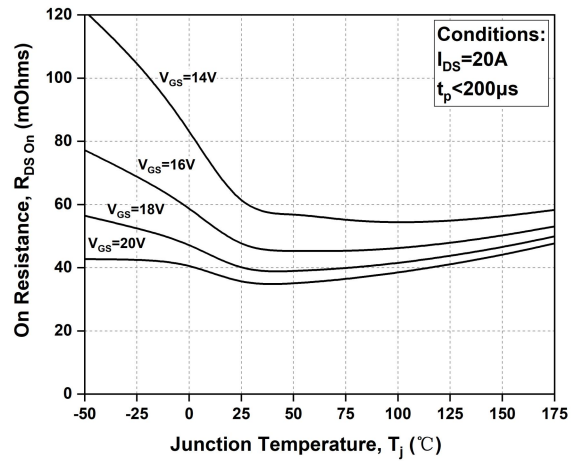


Figure 6. On-resistance vs. temperature for various gate voltage

KXMT120R40T8

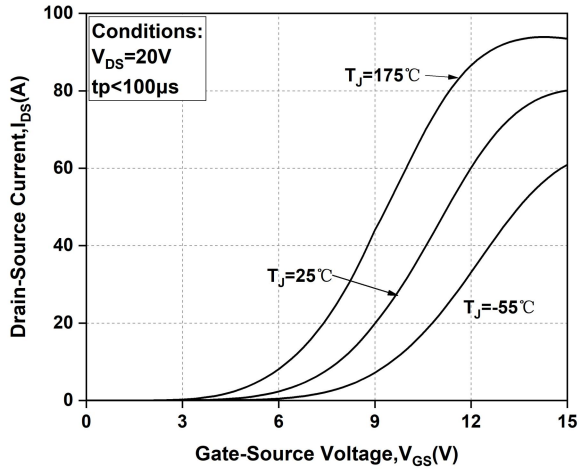


Figure 7. Transfer characteristic for various junction temperatures

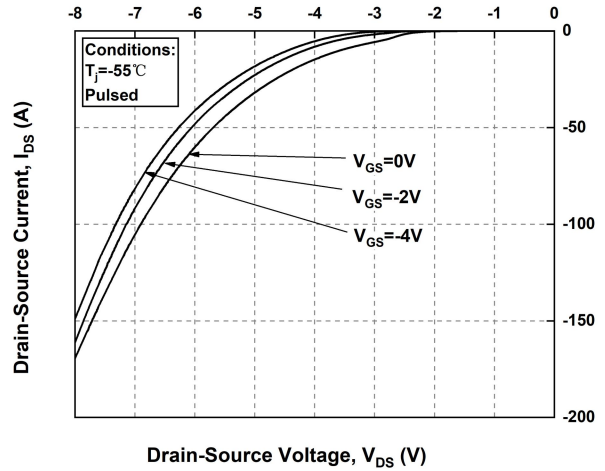


Figure 8. Body diode characteristic at $T_J = -55^\circ\text{C}$

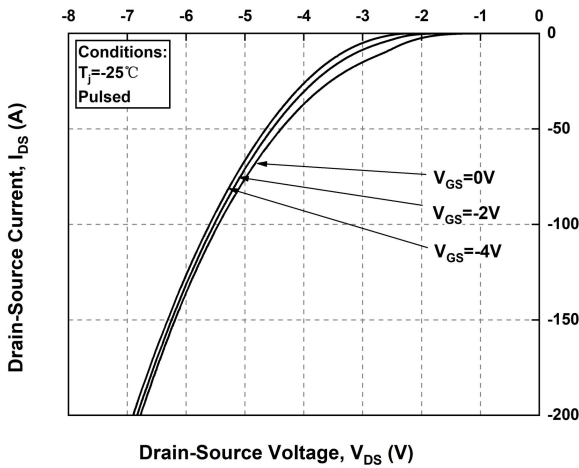


Figure 9. Body diode characteristic at $T_J = 25^\circ\text{C}$

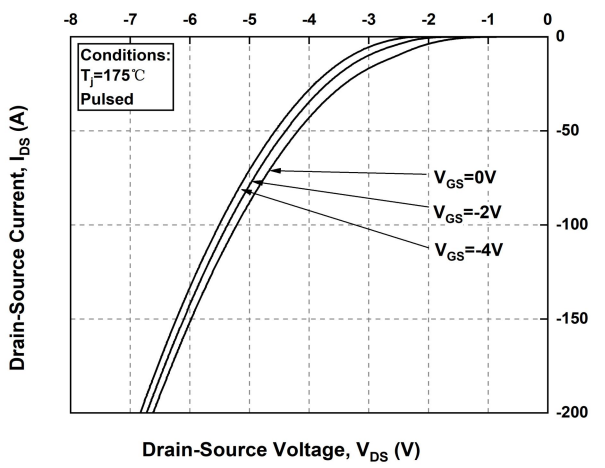


Figure 10. Body diode characteristic at $T_J = 175^\circ\text{C}$

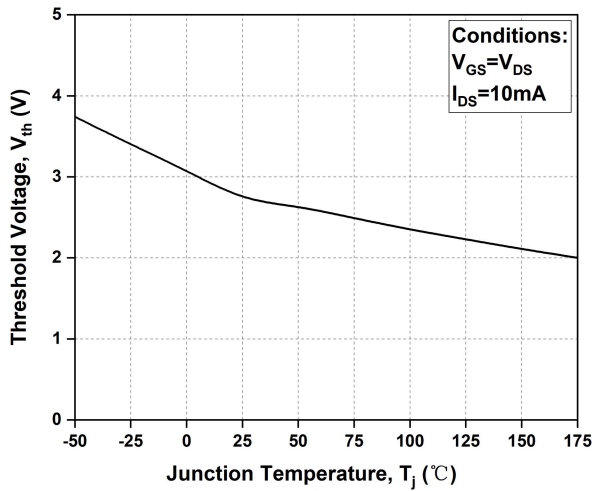


Figure 11. Threshold voltage vs. temperature

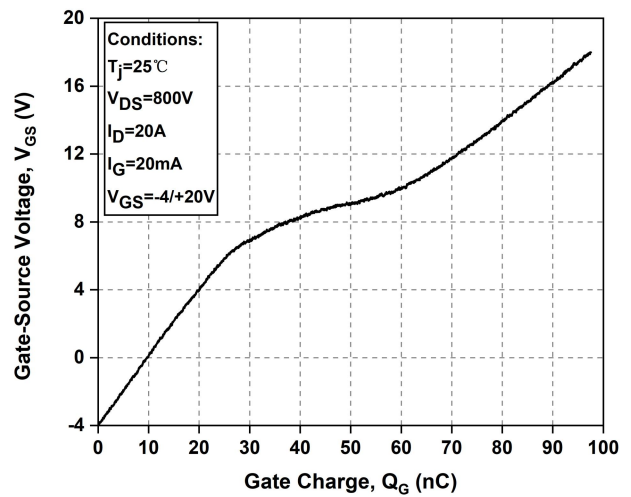


Figure 12. Gate charge characteristic

KXMT120R40T8

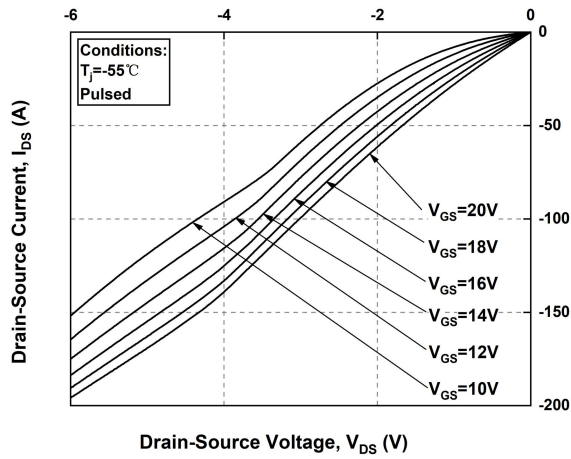


Figure 13. 3rd quadrant characteristic at $T_J = -55^\circ\text{C}$

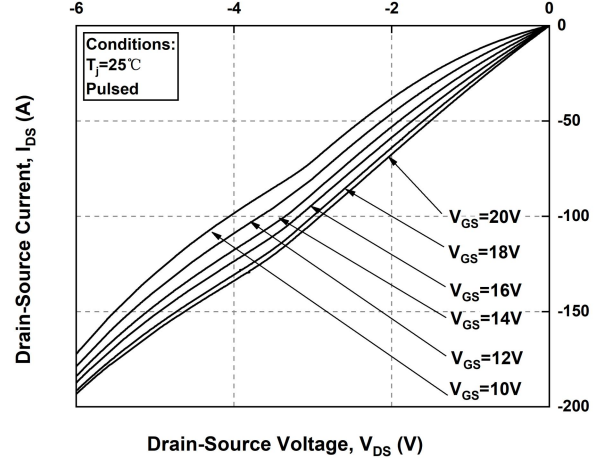


Figure 14. 3rd quadrant characteristic at $T_J = 25^\circ\text{C}$

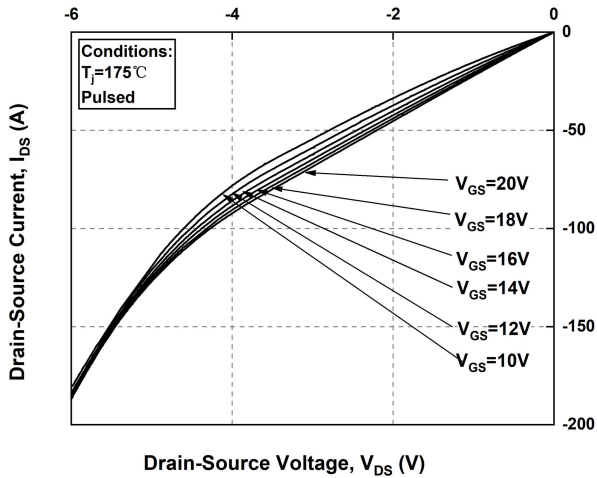


Figure 15. 3rd quadrant characteristic at $T_J = 175^\circ\text{C}$

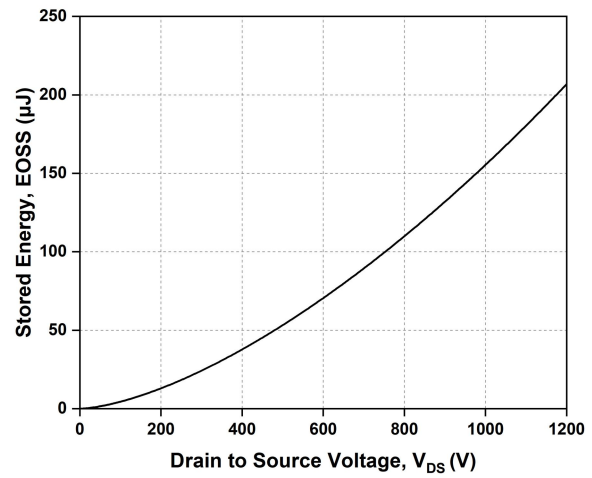


Figure 16. Output capacitor stored energy

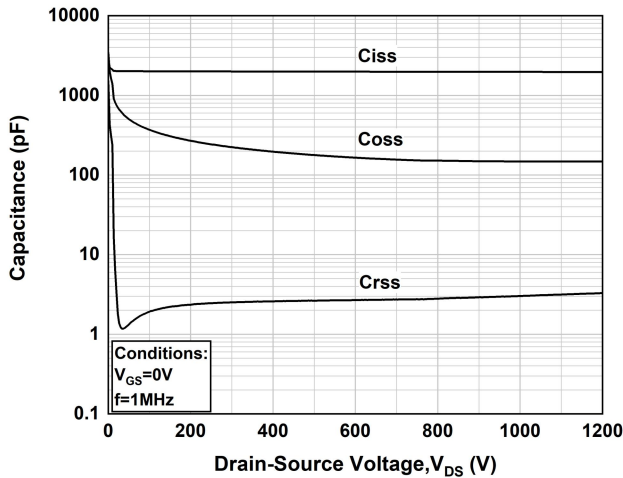


Figure 17. Capacitances vs. drain-source voltage

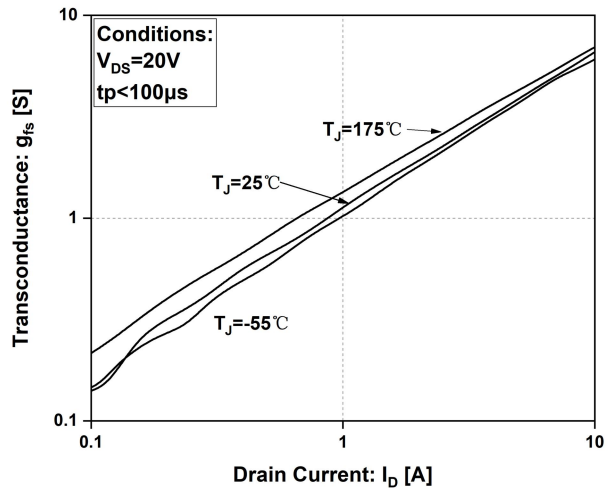


Figure 18. Transconductance vs drain current

KXMT120R40T8

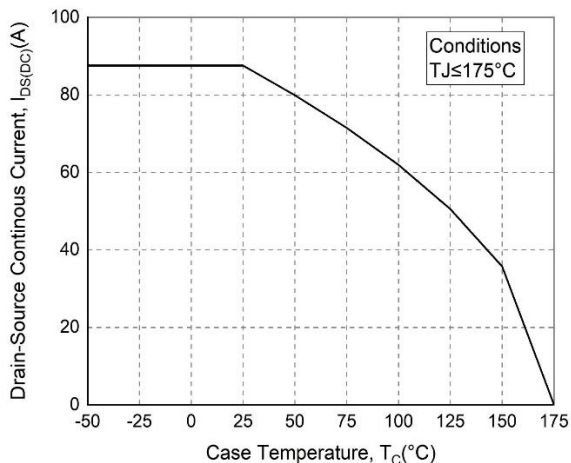


Figure 19. Continuous drain current derating vs. case temperature

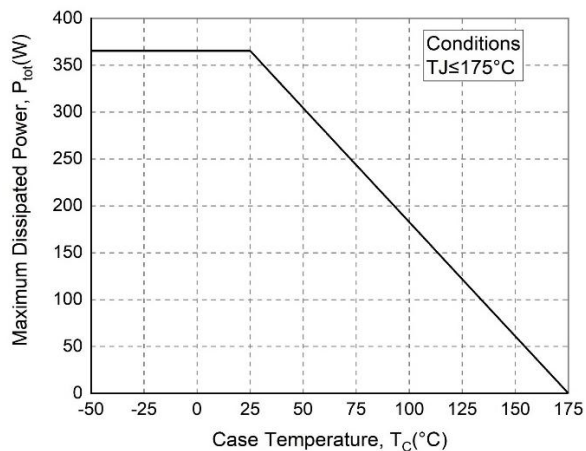


Figure 20. Maximum power dissipation derating vs. case temperature

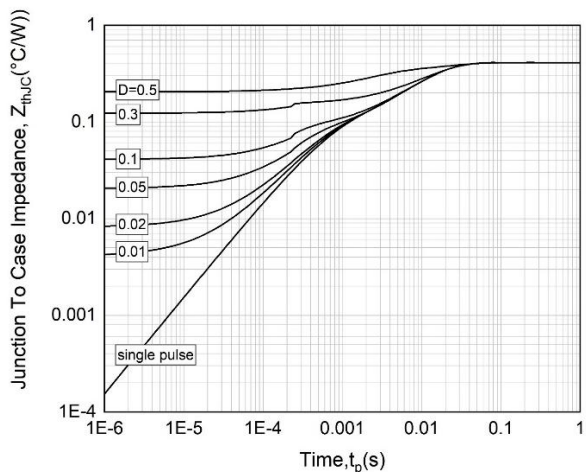


Figure 21. Transient thermal impedance (junction - case)

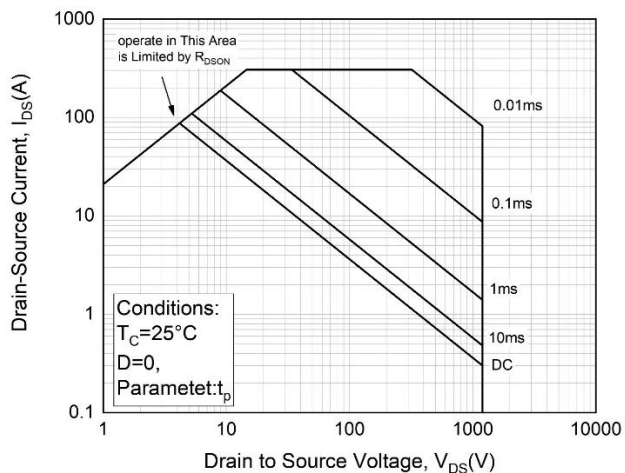


Figure 22. Safe operating area

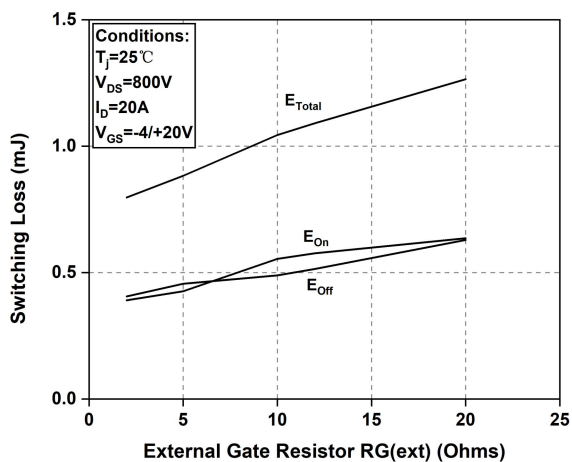


Figure 23. Clamped inductive switching energy vs. $R_G(\text{ext})$

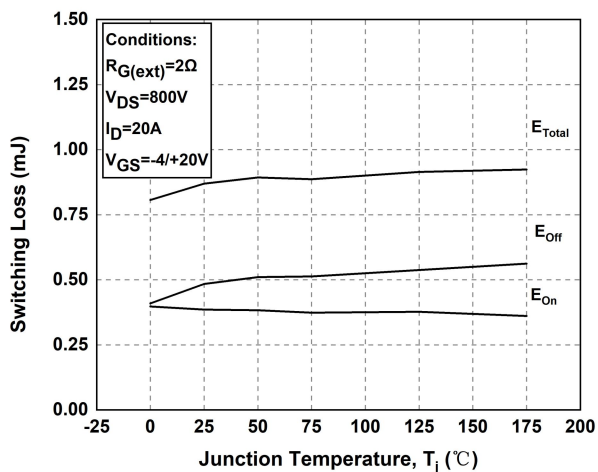


Figure 24. Clamped inductive switching energy vs. temperature

KXMT120R40T8

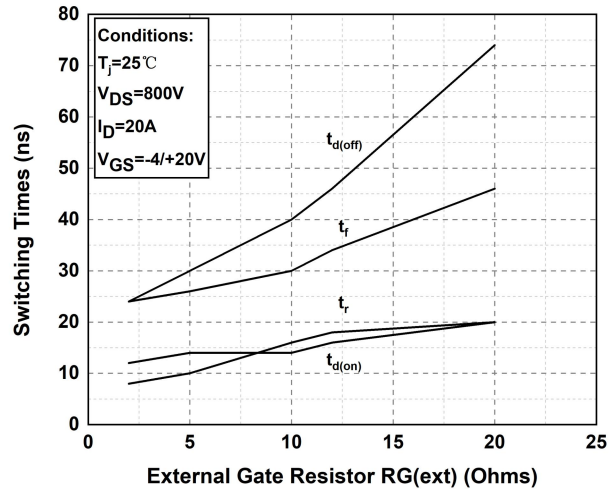
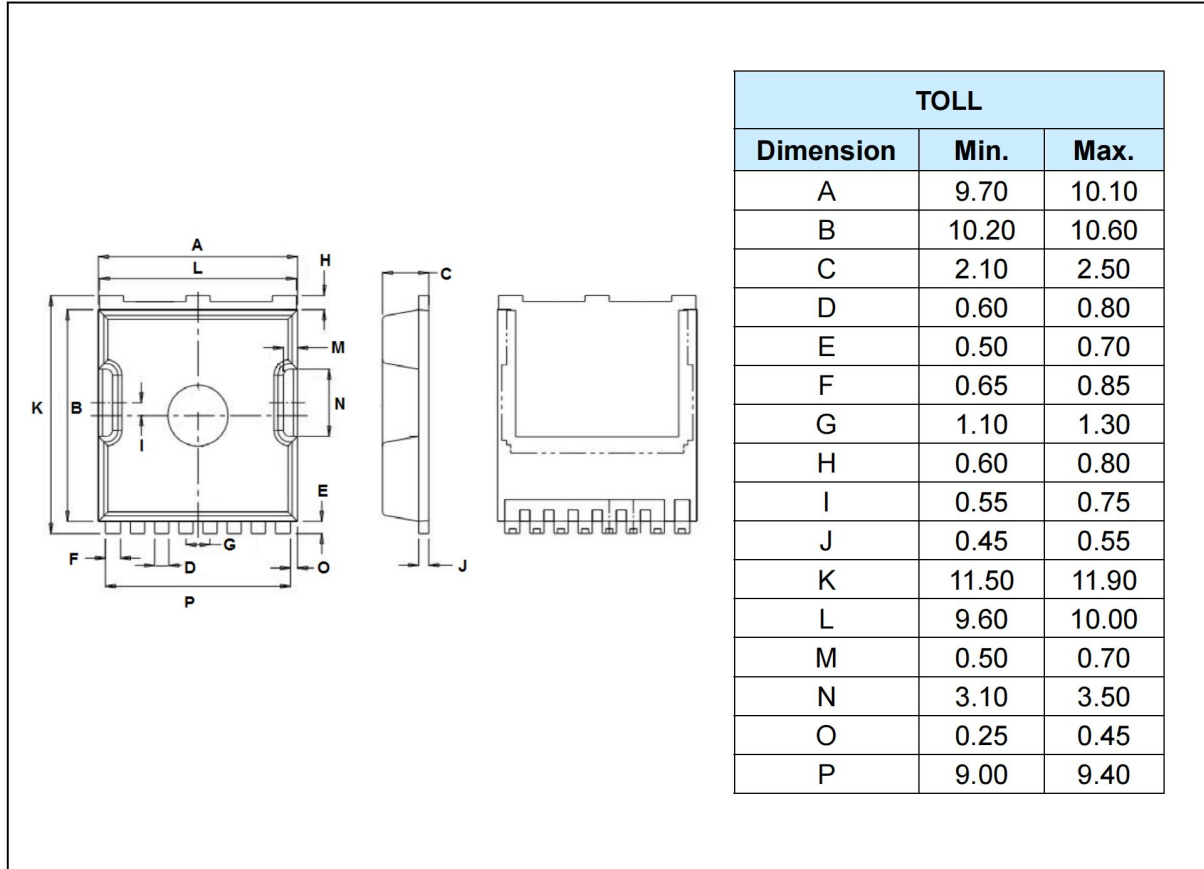


Figure 25. Switching times vs. $R_{G(\text{ext})}$

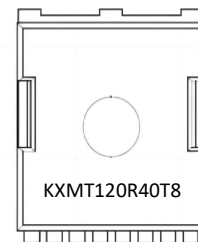
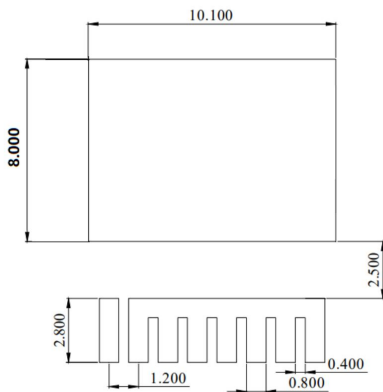
KXMT120R40T8

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
KXMT120R40T8	KXMT120R40T8	TOLL-8L	Tube-on-Lead	N/A	N/A	30 Units



SOLDERING FOOTPRINT



- NOTES: UNLESS OTHERWISE SPECIFIED.
- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
 - B. ALL DIMENSIONS ARE IN MILLIMETERS.
 - C. DRAWING CONFORMS TO ASME Y14.5 - 2009.
 - D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
 - E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.